

Journal of Alloys and Compounds 317-318 (2001) 331-335



www.elsevier.com/locate/jallcom

Structural study of UCuGe_{1.75} by X-ray and electron diffraction

B. Darriet*, B. Chevalier, J. Darriet, S. Pechev

Institut de Chimie de la Matière Condensée de Bordeaux, (ICMCB), CNRS [UPR 9048], Université Bordeaux I, Avenue du Docteur A. Schweitzer, 33608 Pessac, France

Abstract

The new ternary germanide UCuGe_{1.75} have been isolated. After annealing treatment (under vacuum at 1073 K for 1 month), microprobe chemical analysis and X-ray powder diffraction revealed the presence of several phases: major phase corresponds to UCuGe_{1.75(5)} and traces of UGe₂ and UCu₂Ge₂ were present as impurities phases. The refinement of the crystal structure was performed using a single crystal. It crystallises in orthorhombic system with a=0.4052(3) nm, b=1.697(1) nm and c=0.4058(1) nm. The structure of UCuGe_{1.75} corresponds to the TbFeSi₂ structural type. An investigation by transmission electron microscopy (TEM) revealed a substructure $2a \times 2b \times 2c$ which has been explained by a three-dimensional order of vacancies corresponding to the germanium deficit. Moreover the electrical resistivity and magnetization measurements performed on UCuGe_{1.75} revealed the occurrence of anti-ferromagnetic ordering below $T_N = 133(1)$ K. © 2001 Elsevier Science B.V. All rights reserved.

Keywords: Uranium; Ternary germanide; TEM investigation; Antiferromagnetism

1. Introduction

Three intermetallic ternary germanides were reported to exist in the U–Cu–Ge system: UCuGe [1], UCu₂Ge₂ [2] and U₃Cu₄Ge₄ [3,4]. All these compounds exhibit interesting magnetic properties; UCu₂Ge₂ and U₃Cu₄Ge₄ are ferromagnets below $T_{\rm C}$ =110 and 71 K, respectively whereas UCuGe orders antiferromagnetically below $T_{\rm N}$ = 50 K. During the investigation of this system, we have isolated the new ternary germanide UCuGe_{1.75}. We report here on its structural, electrical and magnetic properties investigated by X-ray diffraction (XRD), transmission electron microscopy (TEM), resistivity and magnetization measurements.

2. Experimental details

Three samples having different nominal compositions close to the formulae UCuGe_{1.75} were synthesized by direct melting of the pure elements in an induction levitation furnace under purified argon atmosphere. Then they were annealed in quartz tubes under vacuum at 1073 K for 1 month.

The samples were systematically checked by X-ray

powder diffraction (Cu K α radiation; Guinier camera) and electron microprobe (Cameca SX-100 instrument). The latter analysis was based on the intensity measurements of U M α_1 , Cu K α_1 and Ge K α_1 X-ray emission lines, which were compared with those obtained for UCu₂Ge₂ used as a reference. The crystal X-ray diffraction data were recorded on an Enraf-Nonius CAD-4 four circle diffractometer (Mo K α radiation; graphite monochromator; scintillation counter with pulse height discrimination). The examination by transmission electron microscopy were performed using a JEOL 2000FX apparatus.

Magnetization measurements were performed in the temperature range 5–350 K and in applied magnetic fields up to 4 T using a superconducting quantum interference device (SQUID) magnetometer. Electrical resistivity measurements were carried out between 4.2 and 300 K using a standard four probe DC-technique.

3. Results and discussion

3.1. Microprobe analysis

The three samples were checked by electron microprobe. All contain, as main component, the ternary germanide UCuGe ≥ 1.75 (Table 1). Our results show that it is difficult to obtain this germanide as single phase; parasitic phases as UCu₂Ge₂, 'U₂CuGe₃' and UGe₂ are always

^{*}Corresponding author. Fax: +33-556-842-761.

E-mail address: bdarriet@icmcb.u-bordeaux.fr (B. Darriet).

Table 1 Microprobe analysis of three samples around UCuGe_{1.75} composition

Sample	Nominal	Microprobe analysis		
(11)	composition	Main phase	Parasitic phases	
1	4U + 4Cu + 7Ge	UCuGe _{1.75(5)}	UCu ₂ Ge ₂ , UGe ₂	
2	2.8U + 2.4Cu + 4.8Ge	$UCuGe_{1.69(3)}$	U_2CuGe_3 , UGe_2	
3	1U + 1Cu + 2Ge	UCuGe _{1.67(2)}	UCu ₂ Ge ₂ , U ₂ CuGe ₃	

present. The best sample, sample n°1, corresponds to the nominal composition (4U+4Cu+7Ge), containing the ternary germanide UCuGe_{1.75(5)} with less than 1–2% in mass of UCu₂Ge₂ and UGe₂.

3.2. Single-crystal X-ray diffraction

The examination of the X-ray powder diffraction pattern of sample number 1 indicates: (i) that the major peaks (UCuGe_{1.75} phase) can be indexed on the basis of an orthorhombic unit cell with a=0.4052(3) nm; b=1.6917(1) nm and c=0.4058(1) nm as lattice parameters; (ii) the presence of tetragonal UCu₂Ge₂ [2] and orthorhombic UGe₂ [5] as impurity phases in agreement with the results obtained by microprobe analysis (Table 1). The formula of this new ternary germanide and its unit cell present some analogies with the ternary silicides $UMSi_2$ (M=Fe, Co, Ni, Pt) [6–8] crystallizing with the orthorhombic CeNiSi₂-type structure (space group *Cmcm*).

The structural properties of UCuGe_{1.75} were determined from X-ray diffraction carried out on a single crystal. Buerger and Weissenberg diagrams confirm the orthorhombic symmetry and the only systematic extinction (*hkl* observed with h+k=2n) present corresponds to a C-centred lattice. The space group of UCuGe_{1.75} is *Cmcm*.

This single crystal was then mounted on an automatic four circle diffractometer. After Lorentz-polarisation and absorption corrections 573 independent reflections in the reciprocal space corresponding to $-8 \le h \le 8$, $0 \le k \le 33$, and $0 \le l \le 8$ with $|F_{o}|^{2} > 4\sigma |F_{o}|^{2}$ were measured and kept for the refinement. These data collected using Mo Ka radiation lead to an internal inconsistency index value R_{int} = 0.102. The values of the lattice constants obtained on the four-circle diffractometer are in good agreement with the powder data. Starting from the hypothesis of a CeNiSi₂type structure, the structure of the present germanide was refined using the SHELX 76 PROGRAM [9]. The best result was obtained for the atomic parameters given in Table 2. The conventional residual factor obtained at the final refinement cycle performed with ellipsoidal temperature factors applied to all atoms is 0.079 for 17 variable

Table 2

Atomic parameters of UCuGe_{1.75} (equivalent isotropic thermal parameters B_{eq} given in units of 10^{-2} nm²)

Atom	Site	Positional parameters		Occupancy	$U_{11} \times 10^{3}$	$U_{22} \times 10^{3}$	$U_{33} \times 10^{3}$	B _{eq}	
		x	у	z					
U	4c	0	0.3951(1)	1/4	1	5.84	5.50	5.59	0.45(2)
Cu	4c	0	0.7493(2)	1/4	1	12.31	8.65	10.06	0.82(5)
Ge1	4c	0	0.0283(4)	1/4	0.77(3)	15.50	12.09	58.09	2.3(2)
Ge2	4c	0	0.1690(2)	1/4	1	6.92	21.90	6.14	0.92(4)



Fig. 1. Crystal structure of UCuGe_{1.75}.

parameters. This result leads us to make several comments: (i) we did not be able to get for this phase a single crystal of good quality. In addition the sizes of single crystals founded in our preparation are always very small; (ii) because that uranium atoms are present in this phase the phenomenon of absorption is very important; (iii) the germanium atom Ge1 situated in the site 4c partially occupied has a very high value for the anisotropic temperature factor. The equivalent isotropic thermal parameter calculated is $2.3(2) \times 10^{-2}$ nm². The high value of the composant U_{33} means that the Ge1 atom (z=1/4 fixed) reveals a tendency to be delocalisated along the z-axis; (iv) the composition UCuGe_{1.77(3)} get by refinement of the structure is very close to that determined by electron micropobe analysis (UCuGe_{1.75(5)}).

The structure of UCuGe_{1.75} corresponds to the TbFeSi₂ structural type. The latter is closely related to CeNiSi₂-type structure by an exchange between the positions occupy by transition metal (Ni,Fe) and that of silicium. The structure of UCuGe_{1.75} can be seen along b-axis as a stacking alternated of two arrays of AlB₂ and ThCr₂Si₂ type: AlB_2 -Th Cr_2Si_2 -Al B_2 -Th Cr_2Si_2 -... The site of germanium partially occupied is situated at the centre of a prism $[U_6]$ trigonal prism of AlB₂ type. A projection of the structure along [100] axis is given in Fig. 1. The interatomic distances are listed in Table 3.

3.3. TEM investigation

To get some more structural information an investigation by transition electron microscopy was carried out. Selected-area electron diffraction (SAED) patterns exhibit a lattice of main spots which indexes with the lattice parameters of the unit cell determined by X-ray diffraction. In addition these SAED patterns reveal a second lattice of weak reflections which correspond to a superstructure $2a \times 2b \times 2c$. Any superstructure reflections corresponding to this superstructure have been seen in the X-ray powder diffraction pattern. For example, the SAED pattern of the [-110] zone direction is shown in Fig. 2. This superstructure could be explained by a three-dimensional order of vacancies corresponding to the germanium deficit in his crystallographic position, a phenomenon similar to that

Table 3

Interatomic distances in the structure of UCuGe_{1.75} (standard deviations are all less than or equal 3×10^{-4} nm)

Interatomic distances (nm)					
U-2U 0.4052	Cu-4Cu 0.2868	Ge1-2Ge1 0.2246			
-2U 0.4058	-2Ge2 0.2442	-1Ge2 0.2391			
-2Cu 0.3183	-2Ge2 0.2459				
-2Cu 0.3200					
-2Ge1 0.3038		Ge2-2Cu 0.2442			
-4Ge1 0.3149		-2Cu 0.2459			
-4Ge2 0.3068		-1Ge1 0.2391			

[110]

Fig. 2. Selection area electron diffraction pattern along the [-110] zone axis for UCuGe_{1.75} (indexation is given relative to substructure $2a \times 2b \times$ 2c).

observed before in the silicides YSi_{2-x} , $ErSi_{2-x}$ and Er_3Si_5 [10].

3.4. Electrical and magnetic properties

Fig. 3 presents the temperature dependence of the reduced electrical resistivity for UCuGe_{1.75}. Above 132 K, this temperature dependence is relatively weak and shows



Fig. 3. Temperature dependence of the reduced resistivity of UCuGe_{1.75}.





Fig. 4. Temperature dependence of the reciprocal magnetic susceptibility of $UCuGe_{1.75}$.

a negative coefficient $d\rho/dT$. Below $T_N = 132(2)$ K, the reduced resistivity exhibits an anomalous increase, reaches a maximum at about 70 K and then decreases at lower temperatures. This behaviour, observed previously for $U_3Cu_4Si_4$ [11] and UCu₅ [12] characterizes the occurrence at T_N of an antiferromagnetic ordering; the increase below T_N resulting from the reduction of the number of effective conduction electrons due to the gapping of the Fermi surface caused by the magnetic ordering.

Above 140 K, the magnetic susceptibility of UCuGe_{1.75} follows a Curie–Weiss law: $\chi_{\rm m} = C_{\rm m}/(T - \theta_{\rm p})$ (Fig. 4). A least-squares fit of these data leads to a positive Curie temperature $\theta_{\rm p} = 44(1)$ K and a Curie constant $C_{\rm m} = 1.148$ emu K per U-atom corresponding to an effective magnetic moment of $\mu_{\rm eff.} = 3.03(3) \ \mu_{\rm B}$ per U-atom. The latter value, which is comparable to that determined for the other ternary germanide U₃Cu₄Ge₄ ($\mu_{\rm eff} = 3.19 \ \mu_{\rm B}$) [4], is usually found for uranium in trivalent or tretravalent state.

The temperature dependence of the magnetization of UCuGe_{1.75}, under an applied field B=4T, is shown in Fig. 5. The curve exhibits a peak at $T_{\rm N}=133(1)$ K indicating an antiferromagnetic transition and two increases appearing near 109(1) and 63(1) K, respectively. These two anomalies can be assigned to the ferromagnetic germanides UCu₂Ge₂ ($T_{\rm C}=107$ K) [13] and UGe₂ ($T_{\rm C}=52$ K) [5] which are present in the sample. A best understanding of the antiferromagnetic properties of UCuGe_{1.75} requires the synthesis of a sample without impurities phases.

4. Conclusion

A study of both structural, electrical and magnetic properties of UCuGe_{1.75} has been performed. The crystal structure of UCuGe_{1.75} can be considered as an intergrowth of AlB₂- and ThCr₂Si₂-type slabs. The electrical



Fig. 5. Temperature dependence of the magnetization of UCuGe_{1.75} (inset: derivative curve).

and magnetic measurements reveal an antiferromagnetic ordering at $T_{\rm N} = 133(1)$ K.

References

- [1] J. Leciejewicz, A. Szytula, A. Zygmunt, J. Magn. Magn. Mat. 97 (1991) 219.
- [2] L. Chelmicki, J. Leciejewicz, A. Zygmunt, J. Phys. Chem. Solids 46 (1985) 529.
- [3] D. Kaczorowski, H. Noël, M. Potel, Physica B 206-207 (1995) 457.
- [4] S. Pechev, B. Chevalier, B. Darriet, P. Gravereau, J. Etourneau, J. Alloys Comp. 243 (1996) 77.
- [5] P. Boulet, A. Daoudi, M. Potel, H. Noël, G.M. Gross, G. Andre, F. Bourée, J. Alloys Comp. 247 (1997) 104.

- [6] C. Geibel, C. Kämmerer, E. Göring, R. Moog, G. Sparn, R. Henseleit, G. Cordier, S. Horn, F. Steglich, J. Magn. Magn. Mat. 90–91 (1990) 435.
- [7] N. Sato, M. Kagawa, K. Tanaka, N. Takeda, T. Komatsubara, J. Magn. Magn. Mat. 104–107 (1992) 31.
- [8] D. Kaczorowski, Solid State Commun. 99 (1996) 949.
- [9] G.M. Sheldrick, Shelx-76, Program for crystal structure determination, University of Göttingen, Germany, 1997.
- [10] V. Ghetta, E. Houssay, A. Rouault, R. Madar, B. Lambert, C.R. Acad. Sci. Paris, Série II 309 (1989) 995.
- [11] S. Pechev, B. Chevalier, D. Laffargue, B. Darriet, T. Roisnel, J. Etourneau, J. Magn. Magn. Mat. 191 (1999) 282.
- [12] A. Berbasconi, M. Mombelli, Z. Fisk, H.R. Ott, Z. Phys. B 94 (1994) 423.
- [13] Sk. Mohammad Yusuf, L. Madhav Rao, Phys. Rev. B 53 (1996) 28.